

Wednesday, December 1st, 2021 | 13:00 GMT | 14:00 CET

Please join us for this virtual workshop showcasing the advanced *in-situ* nanoindentation capabilities enabled by our newest instrument: the Hysitron PI 89 PicoIndenter. This live event will **celebrate the re-opening of our PicoIndenter Demonstration Facility in Berlin, Germany**. Our application scientists will give a live demonstration of the advanced testing capabilities of the **PI 89 PicoIndenter** inside the Scanning Electron Microscope (SEM) which will include pillar compression, scratch testing, *in-situ* SPM imaging, and high-speed indentation mapping. We will also discuss the benefits of combining *in-situ* nanoindentation with other Bruker analysis techniques, such as EDS, EBSD etc., and the ease of achieving this with the **Hysitron PI 89 PicoIndenter**.

Who should attend?

Inexperienced nanoindenter users will learn about the benefits of nanoindentation testing inside the Scanning Electron Microscope (SEM) and some of the many research challenges it can solve.

Advanced nanoindenter users will benefit from joining the demonstration and discussion of advanced in-situ techniques and data analysis.

Highlights of the workshop

Meet the team:

Dr Ude Hangen, Applications Manager Dr Jaroslav Lukes, Applications Scientist Dr Rhys Jones, Product Sales Specialist







- Refresh your knowledge of nanoindentation testing inside a Scanning Electron Microscope (SEM)
- Introduction to new and advanced in-situ testing capabilities of the PI 89 PicoIndenter
- Live demonstration from our re-opened European customer demo facility: In-situ nanoindentation, pillar compression, scratch testing, and high-speed indentation mapping etc.
- Tips and tricks for achieving better results from in-situ nanoindentation
- Interactive Q&A session

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- 14:00 Welcome & Introduction Carmen Pettersson, Marcom Manager EMEA
- 14:05 An introduction to main features and functions of the Hysitron PI 89 PicoIndenter, followed by a presentation and demonstration of:
 - Core capabilities, ease-of-use, general operation
 - Basic techniques such as: *in-situ* nanoindentation
 - Advanced techniques such as: pillar compression, high-speed property mapping, scratch testing, in-situ SPM imaging
- 14:45 Interactive Question & Answer session with Dr Ude Hangen and Dr Jaroslav Lukes - *hosted by Dr Rhys Jones*





15:00 End

Please don't hesitate to contact us at productinfo.emea@bruker.com if you have any questions.

Innovation with Integrity